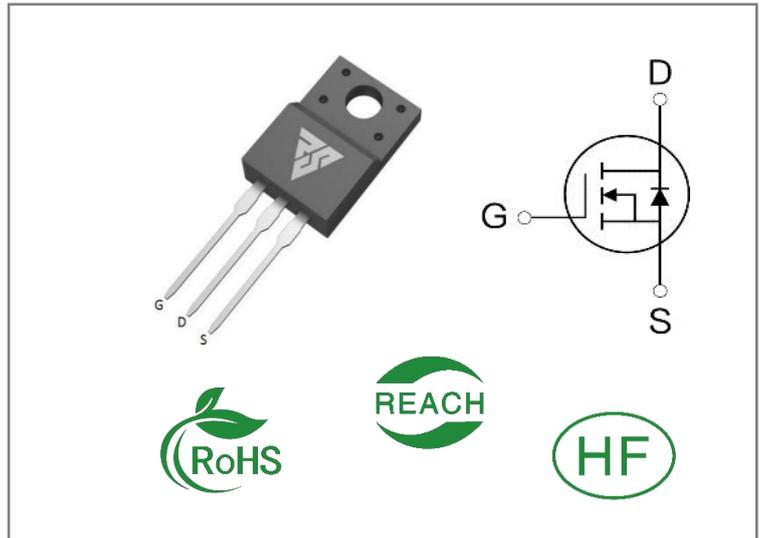


ID	R _{DS(ON)} (Typ)	VDSS
7A	1.1Ω	650V


Applications:

- High efficiency mode power supplies
- Electronic lamp ballasts
- UPS

Features:

- Low Crss
- Low gate charge
- Fast switching
- Improved ESD capability
- Improved dv/dt capability
- 100% avalanche energy test

Ordering Information

Part Number	Package	Marking	Packing	Qty.
RS7N65HF	TO-220F	RS7N65HF	Tube	50 PCS

Absolute Maximum Ratings Tc= 25°C unless otherwise specified

Symbol	Parameter	RS7N65HF	Units
VDSS	Drain-to-Source Voltage	650	V
ID	Continuous Drain Current TC=25°C	7*	A
	Continuous Drain Current TC=100°C	4*	
IDM	Pulsed Drain Current (note 1)	25	
PD	Power Dissipation	48	W
PD(DF)	PowerDissipationDeratingFactor	0.38	W/°C
VGS	Gate- to- Source Voltage	±30	V
EAS	Single Pulse Avalanche Energy (note 2)	245	mJ
IAR	AvalancheCurrent (note 1)	7.0	A
EAR	RepetitiveAvalancheEnergy (note 1)	14.5	mJ
dv/dt	Peak Diode Recovery (note 3)	4.5	V/ns
TL	Maximum Temperature for Soldering	300	°C
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the " Absolute Maximum Ratings" Table may cause permanent damage to the device.

Thermal Resistance

Symbol	Parameter	RS7N65HF	Units	Test Conditions
R θ JC	Junction-to-Case	2.6	°C / W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 °C
R θ JA	Junction-to-Ambient	62.5		1 cubic foot chamber, free air.

OFF Characteristics T_J= 25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage	650	--	--	V	VGS=0V ID=250μA
IDSS	Drain- to- Source Leakage Current	--	--	1	μA	VDS=650V VGS=0V
IGSS	Gate- to- Source Forward Leakage	--	--	100	nA	VGS=30V VDS=0V
	Gate- to- Source Reverse Leakage	--	--	-100		VGS=-30V VDS=0V

ON Characteristics T_J=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On-Resistance	--	1.1	1.4	Ω	VGS=10V ID=3.5A
VGS (TH)	Gate Threshold Voltage	2	--	4	V	VGS=VDS ID=250μA
Gfs	Forward Transconductance (note 4)	--	4	--	S	VDS=40V ID=3.5A

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time	--	42	83	nS	VDS=325V ID=7A RG=25Ω (note 4,5)
trise	Rise Time	--	95	185		
td(OFF)	Turn- OFF Delay Time	--	150	285		
tfall	Fall Time	--	95	190		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	1221	1850	pF	VGS=0V VDS=25V f=1.0MHz
Coss	Output Capacitance	--	99	205		
Crss	Reverse Transfer Capacitance	--	10	18		
Qg	Total Gate Charge	--	43	64	nC	VDS=520V ID=7A VGS=10V (note 4,5)
Qgs	Gate- to- Source Charge	--	7.5	--		
Qgd	Gate-to-Drain(" Miller") Charge	--	24	--		
RG	Gate Resistance	--	3.3	--	Ω	VDS=0V VGS=0V f=1.0MHz

Source- Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	7	A	Integral pn- diode in MOSFET
ISM	Maximum Pulsed Current	--	--	25	A	
VSD	Diode Forward Voltage	--	--	1.4	V	IS=7A,VGS=0V
trr	Reverse Recovery Time	--	415	--	nS	VGS=0V IS=7A di/dt=100A/μs (note 4)
Qrr	Reverse Recovery Charge	--	4.3	--	μC	

Notes:

- 1: Pulse width limited by maximum junction temperature 2: L=10mH, IAS=7A, VDD=50V, RG=25Ω, Starting TJ=25°C
- 3: ISD ≤7A, di/dt ≤300A/μs, VDD≤BVDSS, Starting TJ=25°C
- 4: Pulse Test: Pulse Width ≤300μs, Duty Cycle≤2%
- 5: Essentially independent of operating temperature

Typical Feature Curve

Fig. 1 On-State Characteristics

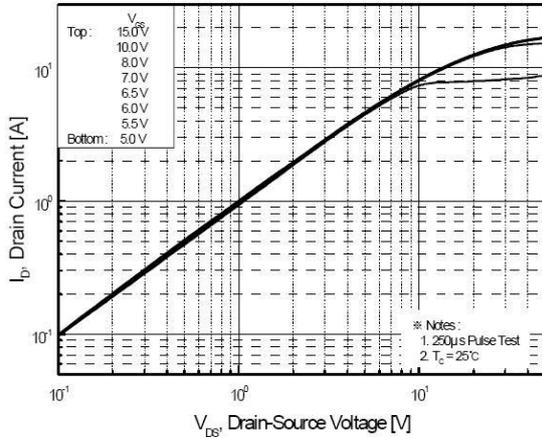


Fig. 2 Transfer Characteristics

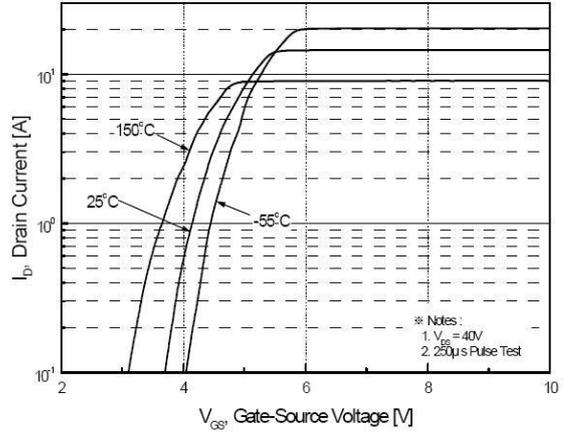


Fig.3 Breakdown Voltage Variation vs Temperature

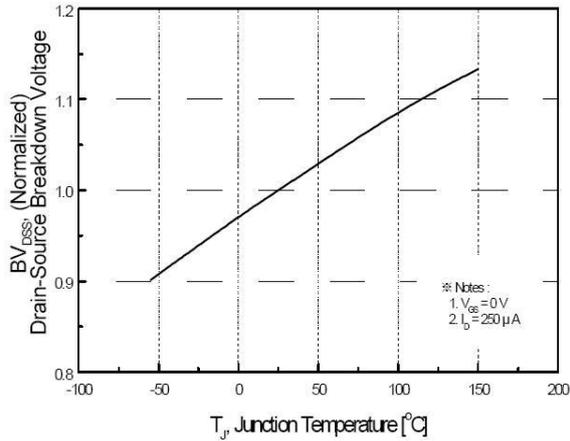


Fig. 4 On-Resistance Variation vs Temperature

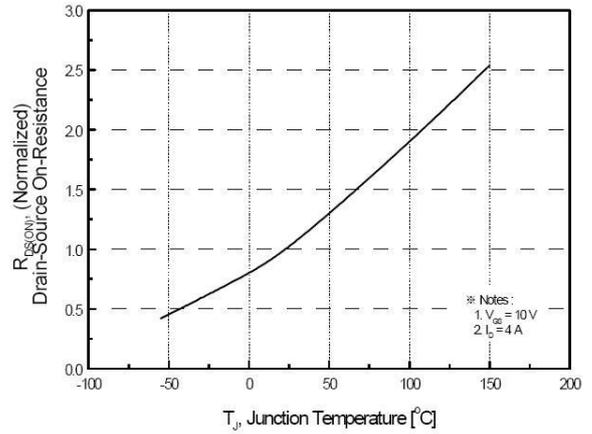


Fig. 5 Capacitance Characteristics

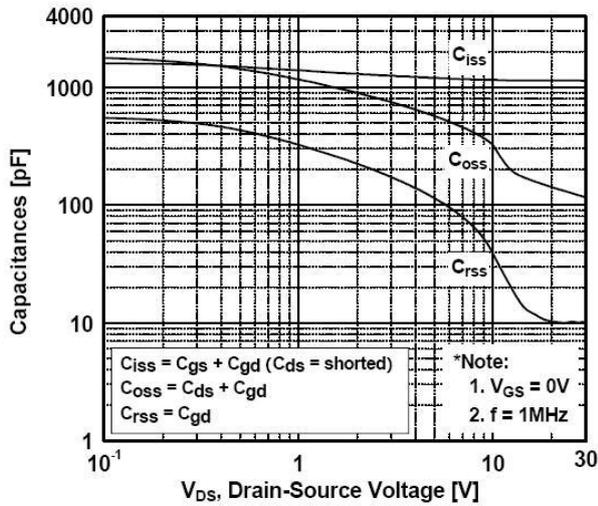
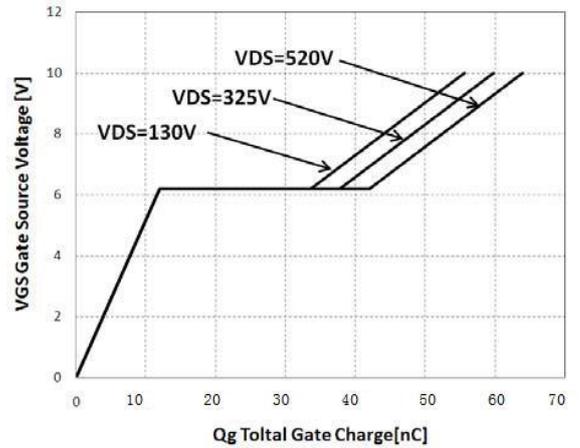


Fig. 6 Gate Charge Characteristics



Typical Feature Curve

Fig.7 Maximum Safe Operating Area

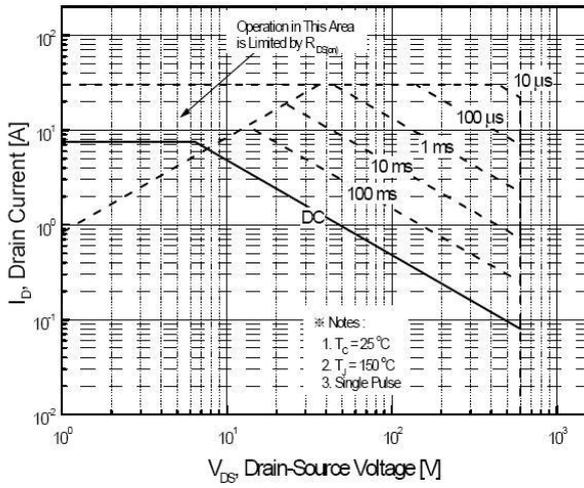


Fig. 8 Maximum Drain Current vs Case Temperature

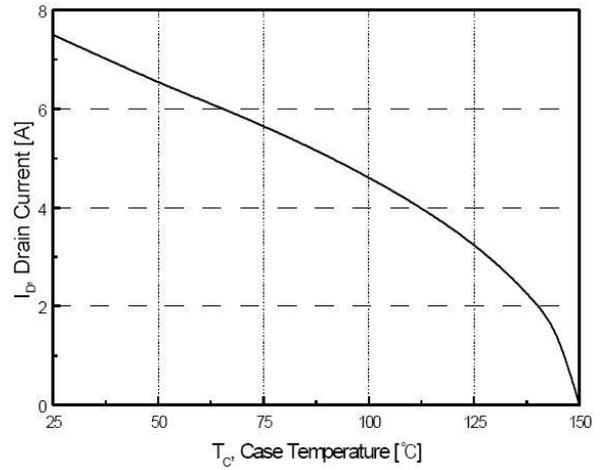
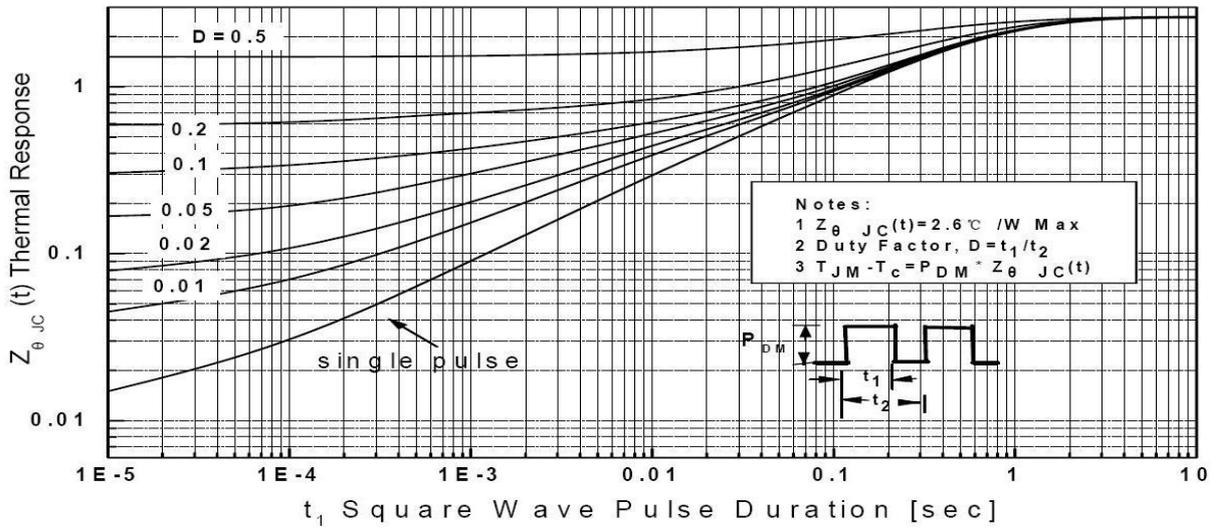
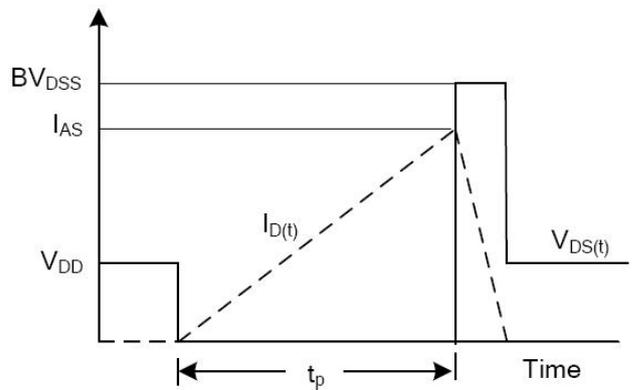
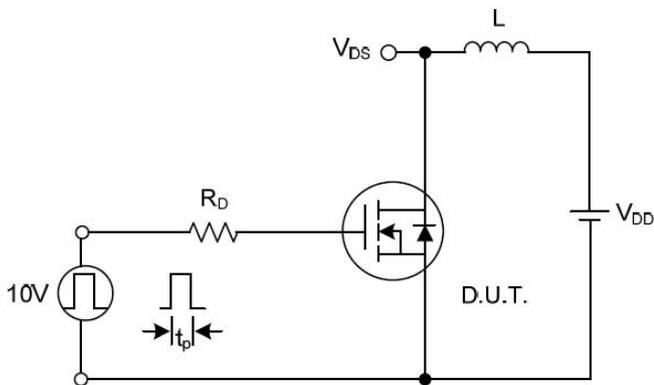
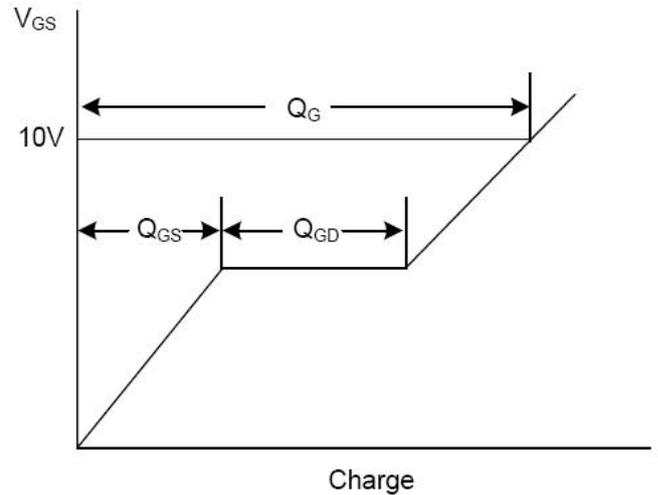
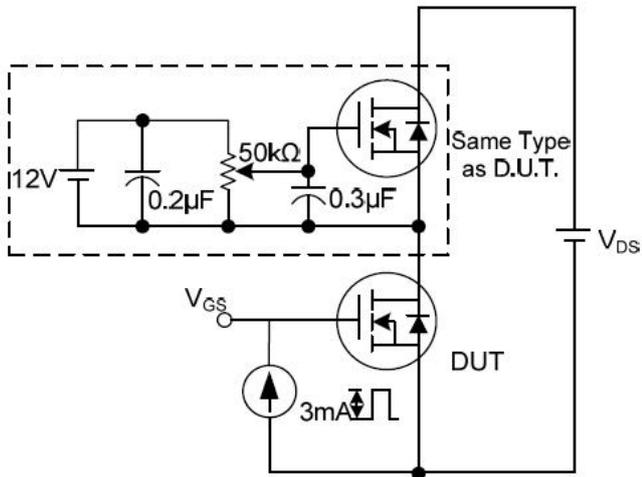
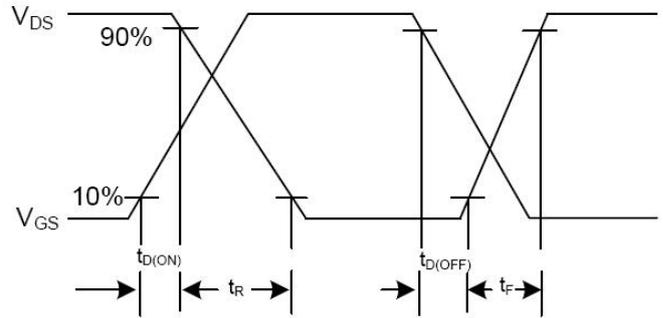
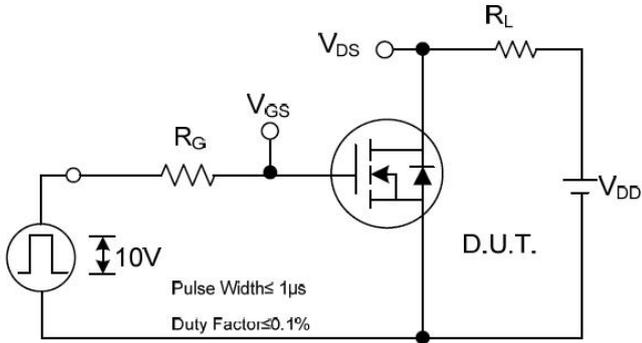


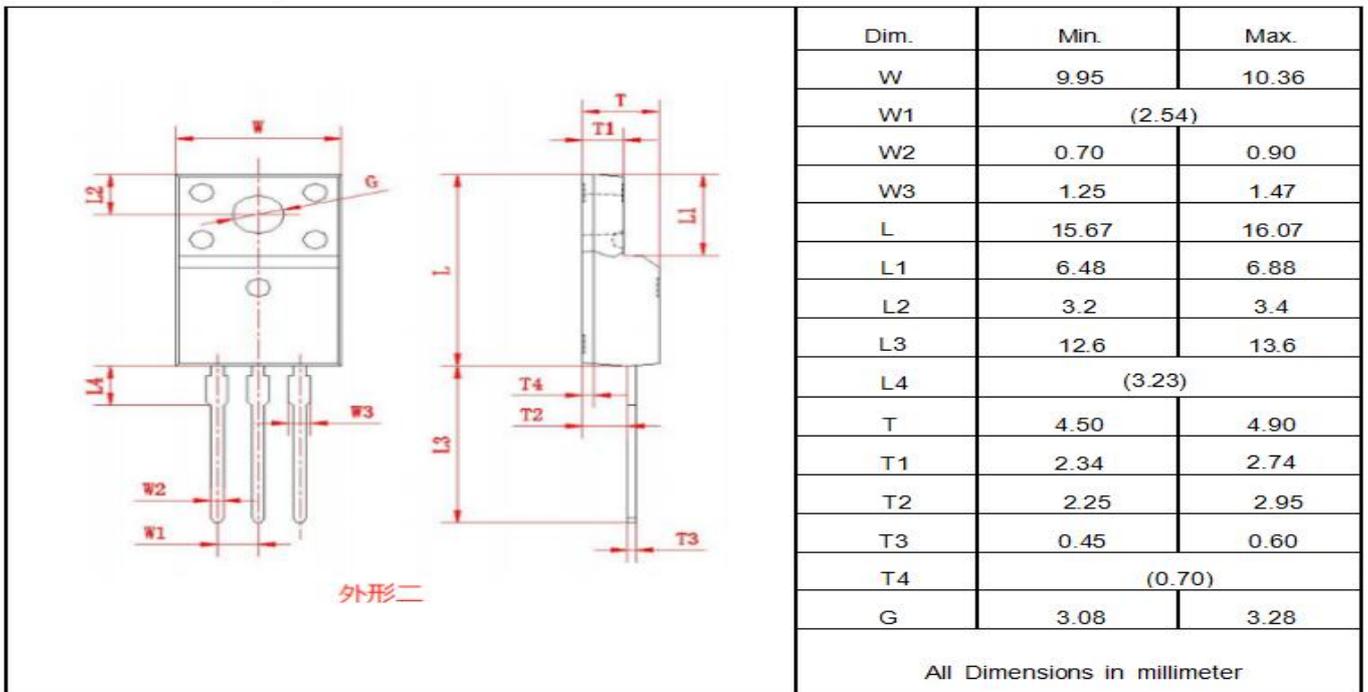
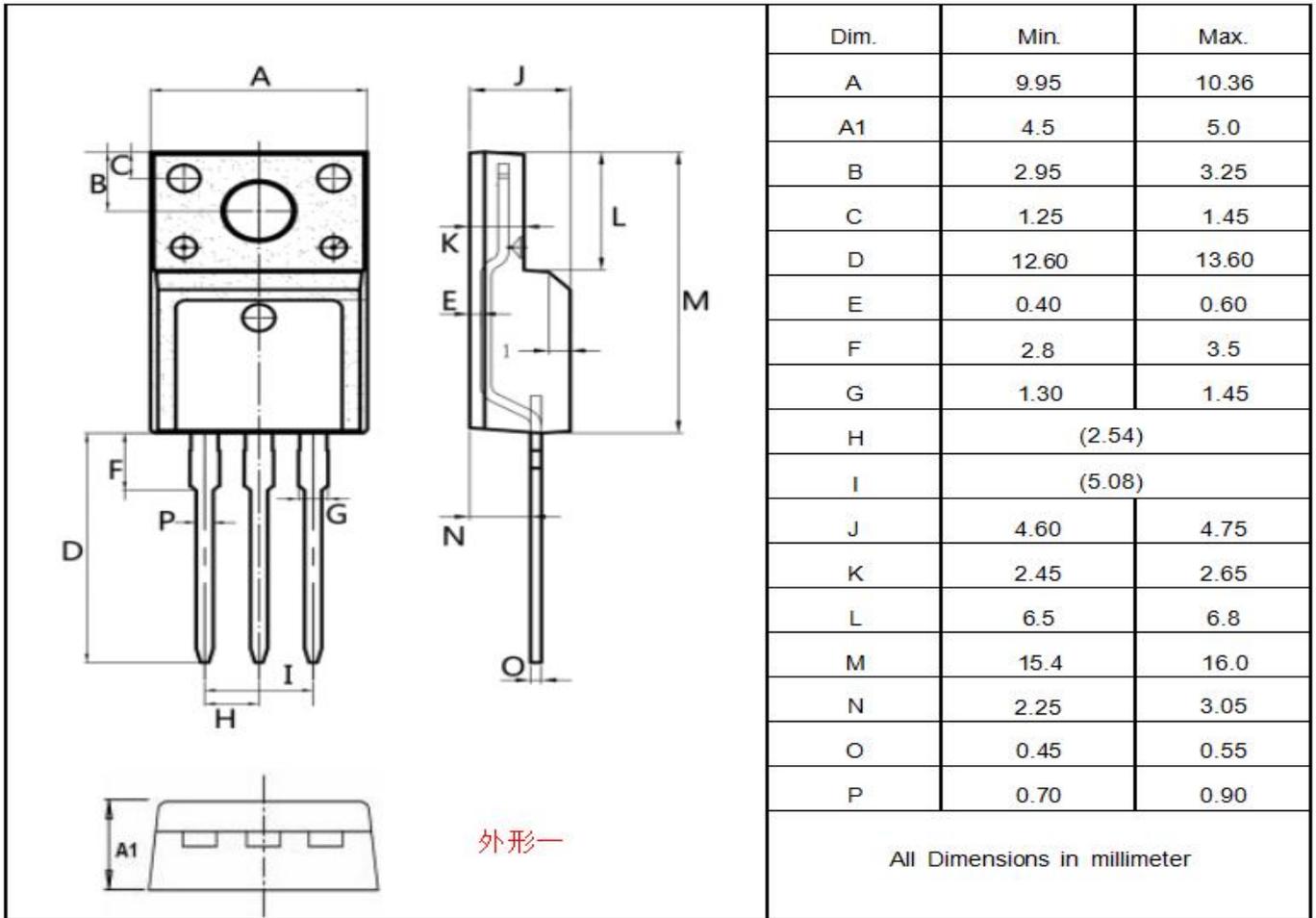
Fig. 9 Transient Thermal Response Curve



Test Circuits and Waveforms



Package outline drawing(TO-220F Unit: mm)



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